



Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/730,188	TAKANASHI ET AL.	
	Examiner	Art Unit	
	Eva Yi Zheng	2611	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
375		229		375	232	350	130		
INTERNATIONAL CLASSIFICATION				360	46	65	66		
H	0	3	H	7/30					
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Eva Zheng 6/15/07 (Assistant Examiner) (Date)		 CHIEH M. FAN SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date) 6/15/07	Total Claims Allowed: 6	
(Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 11	O.G. Print Fig. 1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant					<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
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